C.Dual N-Channel 20-V (D-S) MOSFET

PRODUCT SUMMARY							
V _{DS} (V)	R _{DS(on)} (Ω) MAX.	I _D (A) a	Q _g (TYP.)				
20	0.0085 at V _{GS} = 4.5V	25	14 nC				
20	0.012 at V _{GS} = 2.5 V	22	14110				

FEATURES

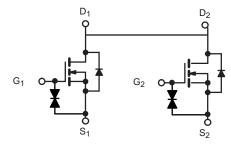
- DT-Trench Power MOSFET
- 100 % R_a and UIS tested
- ESD Protection Diode Embedded



APPLICATIONS

- High power density DC/DC
- Synchronous rectification
- Embedded DC/DC





N-Channel MOSFET

N-Channel MOSFET

PARAMETER	SYMBOL	LIMIT	UNIT	
Drain-Source Voltage	V _{DS}	20	v	
Gate-Source Voltage	V_{GS}	±12		
	T _C = 25 °C		25	
Continuous Drain Current /T 150 °C)	T _C = 70 °C		23	
Continuous Drain Current (T _J = 150 °C)	T _A = 25 °C	I _D	9.0 ^{b, c}	
	T _A = 70 °C		5.4 b, c	
Pulsed Drain Current (t = 300 μs)	I _{DM}	108	A	
Continuous Source-Drain Diode Current	T _C = 25 °C	1	25	
Continuous Source-Drain Diode Current	T _A = 25 °C	I _S	5.1 ^{b, c}	
Single Pulse Avalanche Current	I _ 0.1 mH	I _{AS}	24	
Single Pulse Avalanche Energy	Avalanche Energy L = 0.1 mH		10.3	mJ
	T _C = 25 °C		24	
Maximum Bayyar Dissination	T _C = 70 °C		15.3	w
Maximum Power Dissipation	T _A = 25 °C	P _D	3.1 ^{b, c}	vv
	T _A = 70 °C		1.9 ^{b, c}	
Operating Junction and Storage Temperature R	T _J , T _{stg}	-55 to 150	°C	
Soldering Recommendations (Peak Temperatur		260		

THERMAL RESISTANCE RATINGS							
PARAMETER	SYMBOL	TYPICAL	MAXIMUM	UNIT			
Maximum Junction-to-Ambient b, f	t ≤ 10 s	R _{thJA}	29	45	°C/W		
Maximum Junction-to-Case (Drain)	Steady State	R _{thJC}	4	6	C/VV		

Notes

- a. Based on T_C = 25 °C. b. Surface mounted on 1" x 1" FR4 board.
- d. The DFN3X3 is a leadless package. The end of the lead terminal is exposed copper (not plated) as a result of the singulation process in manufacturing. A solder fillet at the exposed copper tip cannot be guaranteed and is not required to ensure adequate bottom side solder interconnection.
- e. Rework conditions: Manual soldering with a soldering iron is not recommended for leadless components.
- f. Maximum under steady state conditions is 70 °C/W.



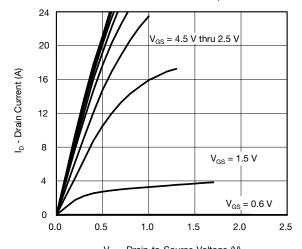
PARAMETER	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Static						
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	20	-	-	V
Drain-Source Breakdown Voltage (transient) c	V _{DSt}	$V_{GS} = 0 \text{ V}, I_{D(aval)} = 15 \text{ A}, t_{transient} = 50 \text{ ns}$	26	-	-	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$		-	20	-	mV/°
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	I _D = 250 μA	-	-4.6	-	С
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_D = 250 \mu\text{A}$	0.5	-	1.5	V
Gate-Source Leakage	I _{GSS}	V _{DS} = 0 V, V _{GS} = 12V	-	-	± 100	nA
Z. o. Oala Wallaca Buria O. oa al	I _{DSS}	V _{DS} = 16 V ,V _{GS} = 0 V	-	-	1	μΑ
Zero Gate Voltage Drain Current		V _{DS} = 16 V ,V _{GS} = 0 V, T _J = 55 °C	-	-	10	
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	25	-	-	Α
Drain-Source On-State Resistance ^a	` ′	V _{GS} = 4.5 V, I _D = 10 A	- 0.0085 0		0.013	
	R _{DS(on)}	V _{GS} = 2.5 V, I _D = 8 A	-	0.012	0.018	Ω
Forward Transconductance a	g _{fs}	V _{DS} = 10 V, I _D = 10 A	-	60	_	S
Dynamic ^b						
Input Capacitance	C _{iss}		-	2050	-	pF
Output Capacitance	Coss	1 ., . <u></u> 1	-	210	-	
Reverse Transfer Capacitance	C _{rss}	$V_{DS} = 10 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$	-	33	-	
Total Gate Charge	Qg	V _{DS} = 10 V, V _{GS} = 4.5 V, I _D = 10 A	-	19	-	nC
			-	10	-	
Gate-Source Charge	Q _{gs}	$V_{DS} = 10 \text{ V}, V_{GS} = 2.5 \text{ V}, I_D = 8 \text{ A}$	-	4	-	
Gate-Drain Charge	Q _{gd}		-	1.8	-	
Output Charge	Q _{oss}	V _{DS} = 10 V, V _{GS} = 0 V	-	12.5	-	
Gate Resistance	Rg	f = 1 MHz	0.4	1.60	3.3	Ω
Turn-On Delay Time	t _{d(on)}		-	9	18	
Rise Time	t _r	$V_{DD} = 10 \text{ V}, R_1 = 1.5 \Omega$	-	8	16	
Turn-Off Delay Time	t _{d(off)}	$I_{D} \cong 10 \text{ A}, V_{GEN} = 4.5 \text{ V}, R_g = 1\Omega$		18	36	†
Fall Time	t _f		-	8	16	
Turn-On Delay Time	t _{d(on)}		-	15	30	ns
Rise Time	t _r	$V_{DD} = 10 \text{ V, R}_{L} = 1.5 \Omega$	-	12	24	
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 8 \text{ A, } V_{GEN} = 2.5 \text{ V, } R_g = 1 \Omega$	-	18	36	
Fall Time	t _f	1	-	9	18	
Drain-Source Body Diode Characteristics	· · · · · · · · · · · · · · · · · · ·			ı		
Continuous Source-Drain Diode Current	Is	T _C = 25 °C	-	- 1	25	
Pulse Diode Forward Current ^a	I _{SM}	-	-	-	108	A
Body Diode Voltage	V _{SD}	I _S = 3 A	-	0.70	1.2	V
Body Diode Reverse Recovery Time	t _{rr}	19 - 0 11		24	48	ns
Body Diode Reverse Recovery Charge	Q _{rr}	I _F = 10 A, dl/dt = 100 A/μs,	-	14	28	nC
Reverse Recovery Fall Time	ta	$T_{\rm J} = 25 ^{\circ}{\rm C}$	-	12	-	1
Reverse Recovery Rise Time	t _b			12		ns

Notes

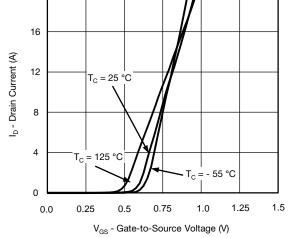
- a. Pulse test; pulse width $\leq 300~\mu s,$ duty cycle $\leq 2~\%.$
- b. Guaranteed by design, not subject to production testing.
- c. $T_{CASE} = 25$ °C. Expected voltage stress during 100 % UIS test. Production datalog is not available.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

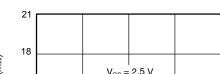


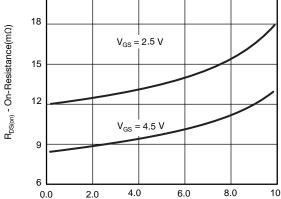


 ${\rm V}_{\rm DS}$ - Drain-to-Source Voltage (V) **Output Characteristics**

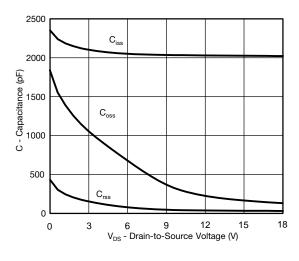


Transfer Characteristics

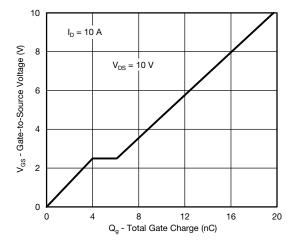




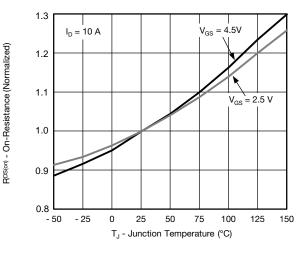
I_D - Drain Current (A) On-Resistance vs. Drain Current



Capacitance

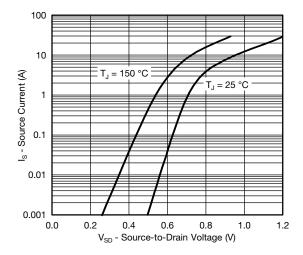


Gate Charge

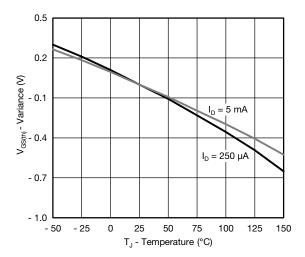


On-Resistance vs. Junction Temperature

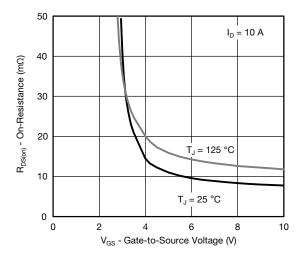




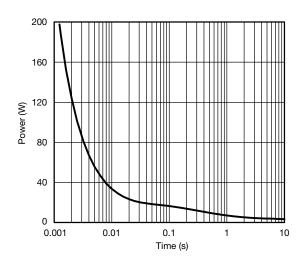
Source-Drain Diode Forward Voltage



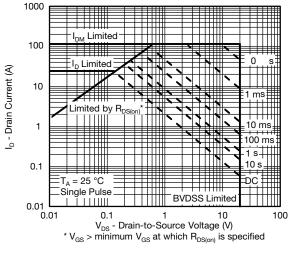
Threshold Voltage



On-Resistance vs. Gate-to-Source Voltage

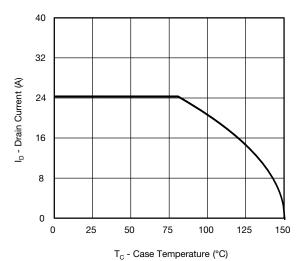


Single Pulse Power, Junction-to-Ambient

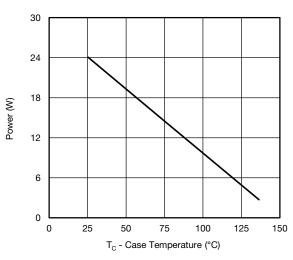


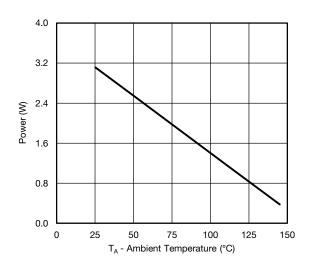
Safe Operating Area





Current Derating*

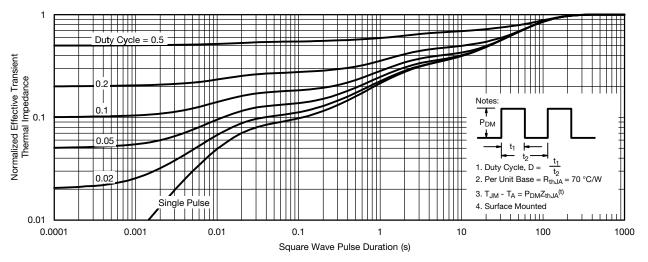




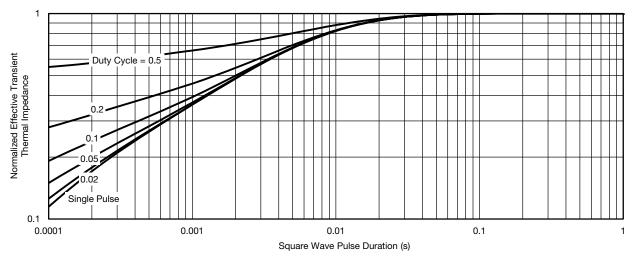
Power, Junction-to-Case Power, Junction-to-Ambient

 $^{^*}$ The power dissipation P_D is based on $T_{J \text{ (max.)}} = 150 \,^{\circ}\text{C}$, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





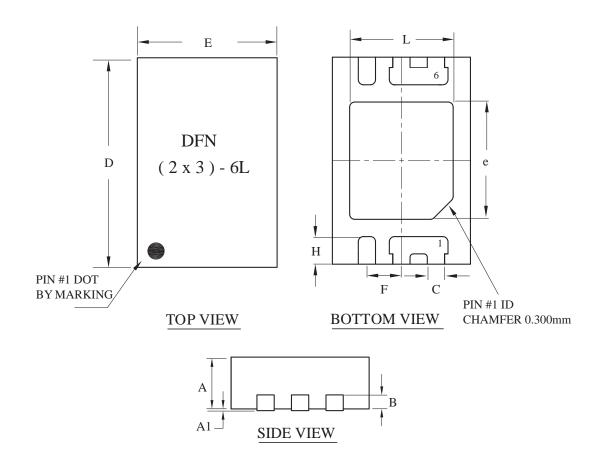
Normalized Thermal Transient Impedance, Junction-to-Ambient



Normalized Thermal Transient Impedance, Junction-to-Case



DFN2*3-6L PACKAGE OUTLINE



SYMBOLS	MILLI	METERS	INCHES		
	MIN	MAX	MIN	MAX	
A	0.600	0.900	0.027	0.035	
A1	0.000	0.060	0.000	0.002	
D	2.750	3.250	0.108	0.128	
E	1.800	2.300	0.071	0.091	
Н	0.250	0.600	0.010	0.024	
L	1.300	1.700	0.051	0.067	
e	1.500	1.900	0.059	0.075	
В	0.185	0.225	0.0073	0.0089	
C	0.175	0.335	0.007	0.013	
F	0.500 BSC		0.020 BSC		





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